FAIRCHILD SEMICONDUCTOR™

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DM7400
Quad 2-Input NAND Gates

General Description

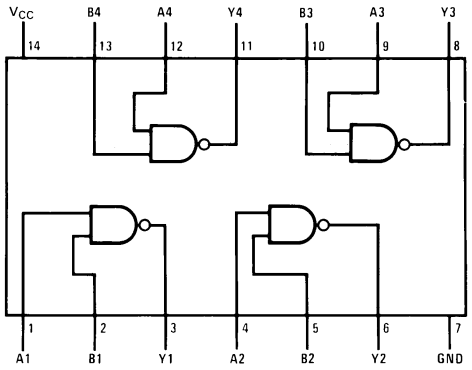
This device contains four independent gates each of which performs the logic NAND function.

Ordering Code:

Order Number	Package Number	Package Description
DM7400M	M14A	14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-012, 0.150 Narrow
DM7400N	N14A	14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Connection Diagram



Function Table

$Y = \overline{AB}$

Inputs		Output
A	B	Y
L	L	H
L	H	H
H	L	H
H	H	L

H = HIGH Logic Level
L = LOW Logic Level

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Absolute Maximum Ratings(Note 1)

Supply Voltage	7V
Input Voltage	5.5V
Operating Free Air Temperature Range	0°C to +70°C
Storage Temperature Range	−65°C to +150°C

Note 1: The "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. The device should not be operated at these limits. The parametric values defined in the Electrical Characteristics tables are not guaranteed at the absolute maximum ratings. The "Recommended Operating Conditions" table will define the conditions for actual device operation.

Recommended Operating Conditions

Symbol	Parameter	Min	Nom	Max	Units
V_{CC}	Supply Voltage	4.75	5	5.25	V
V_{IH}	HIGH Level Input Voltage	2			V
V_{IL}	LOW Level Input Voltage			0.8	V
I_{OH}	HIGH Level Output Current			−0.4	mA
I_{OL}	LOW Level Output Current			16	mA
T_A	Free Air Operating Temperature	0		70	°C

Electrical Characteristics

over recommended operating free air temperature range (unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ (Note 2)	Max	Units
V_I	Input Clamp Voltage	V_{CC} = Min, I_I = −12 mA			−1.5	V
V_{OH}	HIGH Level Output Voltage	V_{CC} = Min, I_{OH} = Max V_{IL} = Max	2.4	3.4		V
V_{OL}	LOW Level Output Voltage	V_{CC} = Min, I_{OL} = Max V_{IH} = Min		0.2	0.4	V
I_I	Input Current @ Max Input Voltage	V_{CC} = Max, V_I = 5.5V			1	mA
I_{IH}	HIGH Level Input Current	V_{CC} = Max, V_I = 2.4V			40	μA
I_{IL}	LOW Level Input Current	V_{CC} = Max, V_I = 0.4V			−1.6	mA
I_{OS}	Short Circuit Output Current	V_{CC} = Max (Note 3)	−18		−55	mA
I_{CCH}	Supply Current with Outputs HIGH	V_{CC} = Max		4	8	mA
I_{CCL}	Supply Current with Outputs LOW	V_{CC} = Max		12	22	mA

Note 2: All typicals are at V_{CC} = 5V, T_A = 25°C.

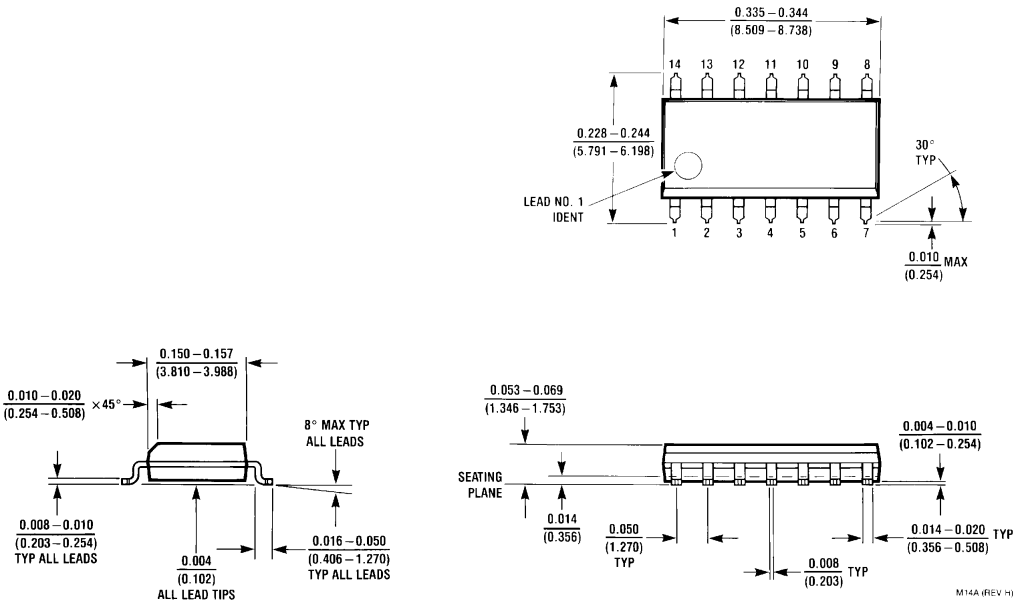
Note 3: Not more than one output should be shorted at a time.

Switching Characteristics

at V_{CC} = 5V and T_A = 25°C

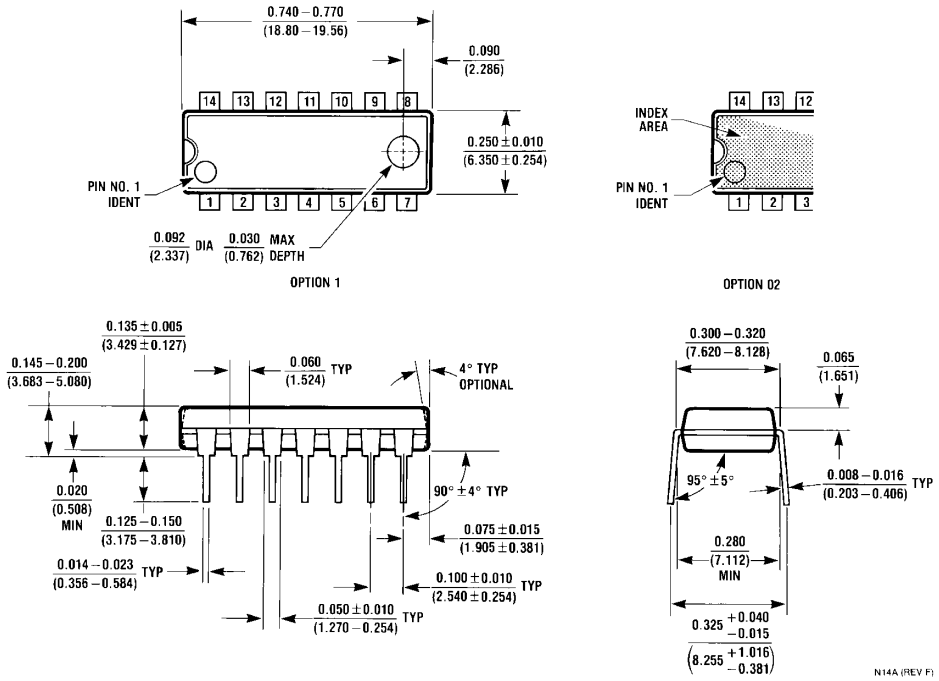
Symbol	Parameter	Conditions	Min	Max	Units
t_{PLH}	Propagation Delay Time LOW-to-HIGH Level Output	C_L = 15 pF R_L = 400Ω		22	ns
t_{PHL}	Propagation Delay Time HIGH-to-LOW Level Output			15	ns

Physical Dimensions inches (millimeters) unless otherwise noted



14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-012, 0.150 Narrow
Package Number M14A

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide
Package Number N14A

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